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**AEHR TEST SYSTEMS RECEIVES
ADDITIONAL WAFER-LEVEL CONTACT PATENTS**

Fremont, CA (July 28, 2003) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of test and burn-in equipment to semiconductor manufacturers, today announced that it has been issued three additional patents from the U.S. Patent and Trademark Office relating to its wafer-level burn-in and test technology.

The patents cover various aspects of the wafer burn-in and test method that first places wafers in a test cartridge to allow multiple wafers to be burned-in and tested simultaneously by a single system. This results in optimal use of the tester electronics and maximizes system throughput.

“These patents are key to our FOX™ full wafer contact family of products,” said C.J. Meurell, president and chief operating officer of Aehr Test. “They recognize some of the innovations we have made during our development of the FOX products.”

Rhea Posedel, chairman and chief executive officer of Aehr Test, said, “We have been investigating and developing the fundamental technologies required for full wafer contact for ten years. We are very pleased to be granted these patents that acknowledge the many unique concepts and methods we have invented.”

The FOX full wafer contact products share a common feature — the ability to contact all die on a wafer simultaneously. This allows semiconductor products to be burned-in and tested while still in wafer form. This is very important in the production of fully burned-in and tested bare die for use in miniature devices ranging from cellular telephones to portable music players.

The most recent patents issued to Aehr Test are the following:

- U.S. Patent No. 66,556,032 (Wafer Burn-in and Test Employing Detachable Cartridge)
- U.S. Patent No. 66,562,636 (Wafer-Level Burn-in and Electrical Test System and Method)
- U.S. Patent No. 66,580,283 (Wafer-Level Burn-in and Test Methods)

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX, MAX3 and MAX4 systems, and the DiePak[®] carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com

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